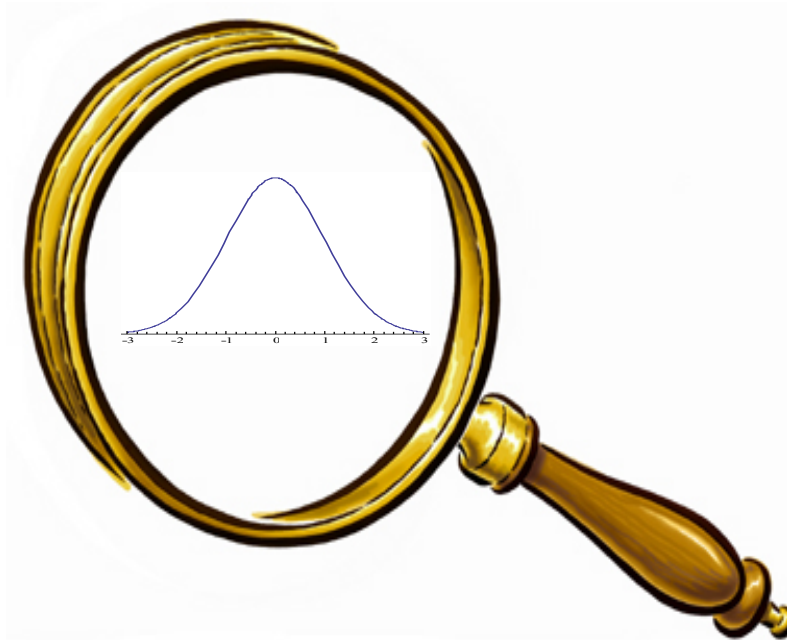


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# Quantitative Firearms and Toolmark Analysis: New Developments and Software



Petraco Group  
City University of New York, John Jay College

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# Outline

- 3D toolmark data, pre-processing and feature extraction: **x3pr**, **feature2**
- The statistics:
  - Identification Error Rates
  - “Match” confidence estimate from Conformal Prediction Theory: **cptID**
  - “Match” probability estimates from Empirical Bayes: **fdrID**
  - “Match” probability estimates from CMS data and Bayesian Networks

# Data Acquisition For Toolmarks

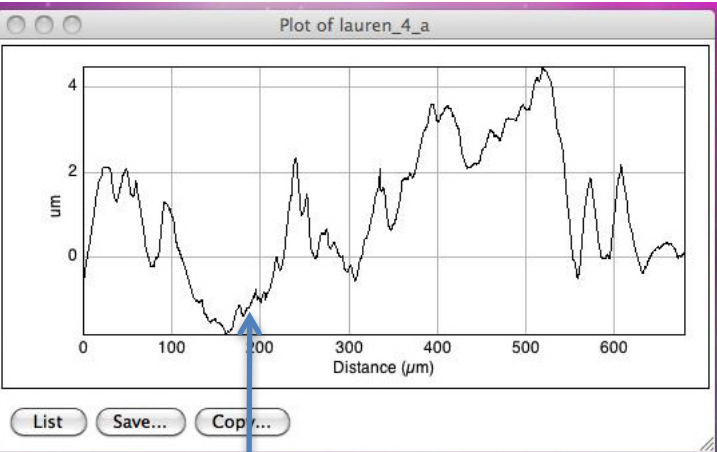
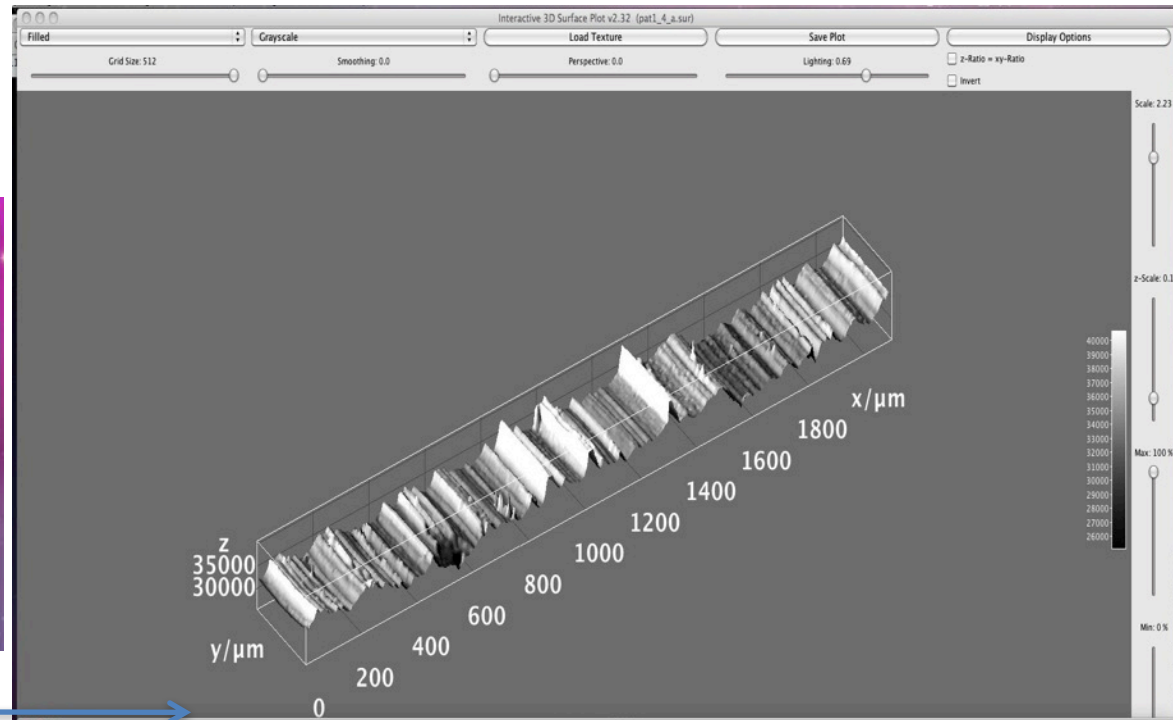
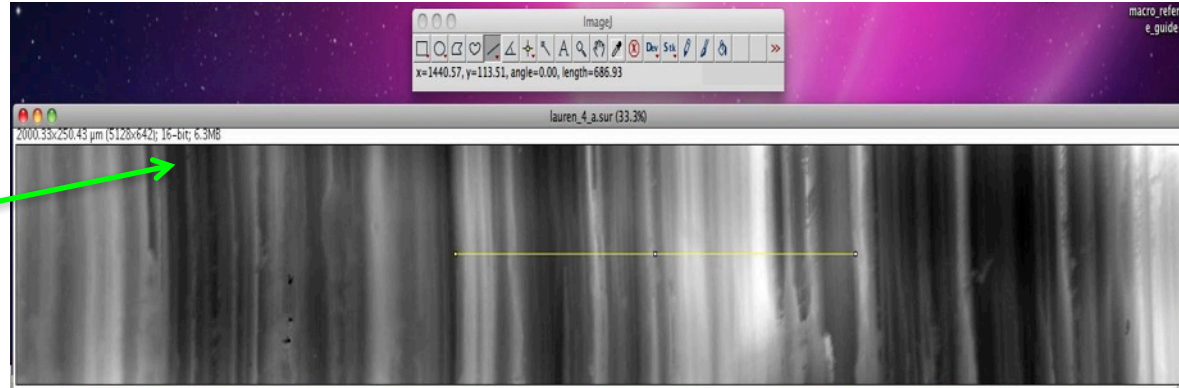


Confocal Microscope



Focus Variation Microscope

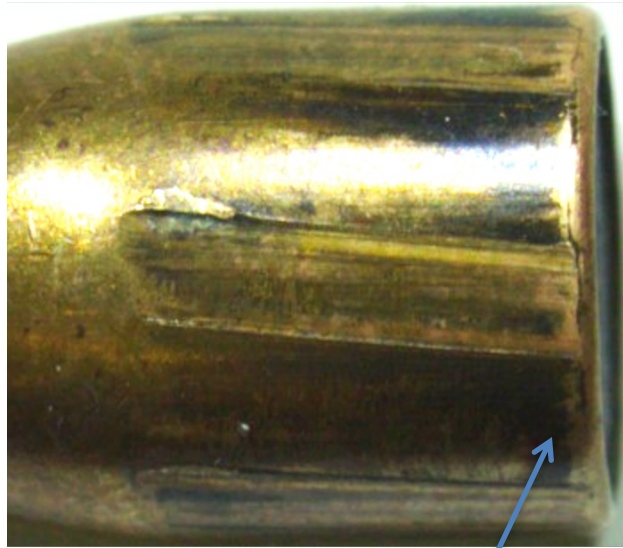
# Screwdriver Striation Patterns in Lead



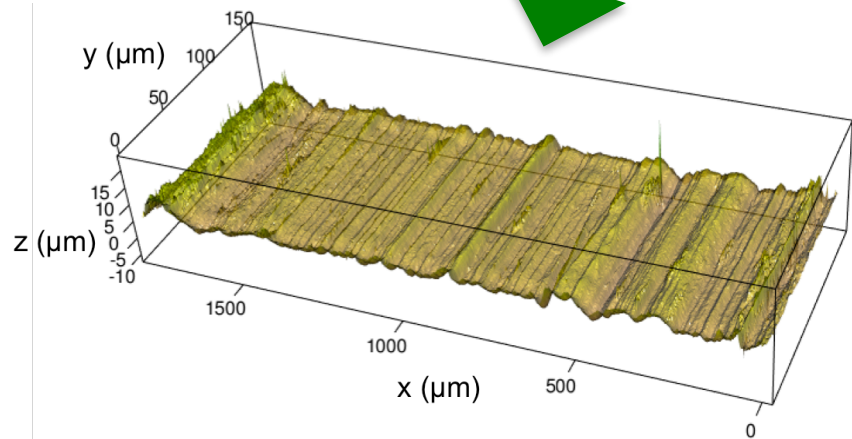
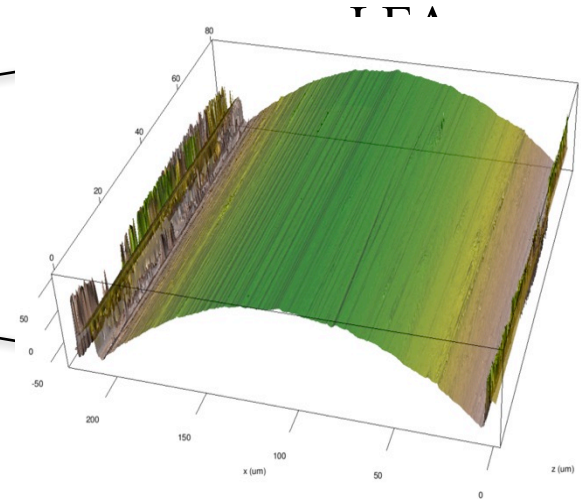
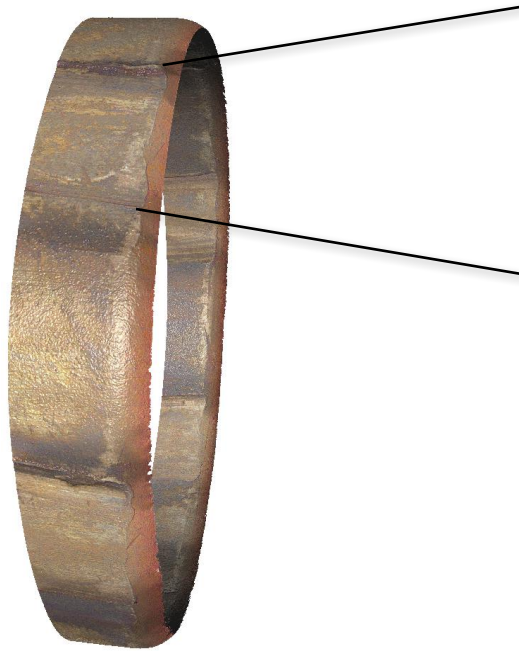
2D profiles

3D surfaces  
(interactive)

# Bullets



Bullet base, 9mm Ruger Barrel

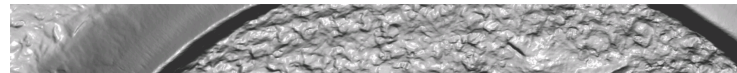


# Toolmark Surface Data

- A growing database<sup>Zheng</sup>:
  - <http://www.nist.gov/forensics/ballisticsdb/>



- Put in your two cents: OpenFMC<sup>Lillien</sup>
  - <http://www.openfmc.org/>

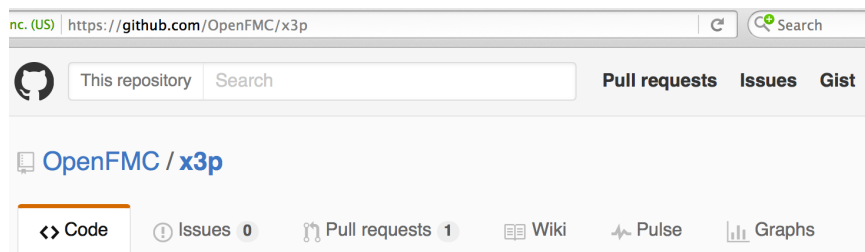


# Toolmark Surface Data

- Standardizing file format: .x3p
  - <http://www.nist.gov/forensics/ballisticsdb/dataformat.cfm>

x3p C++/  library, Windows <sup>Brubaker</sup>

x3pr <sup>Petraco</sup> for , Any OS



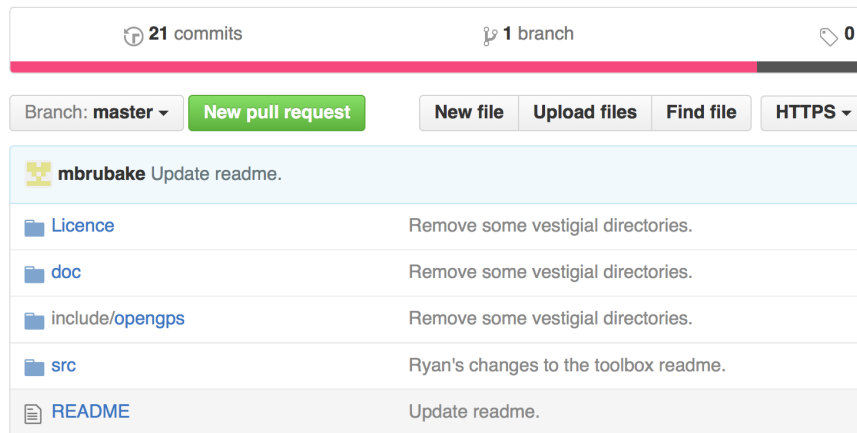
nc. (US) | <https://github.com/OpenFMC/x3p> Search

This repository Search Pull requests Issues Gist

OpenFMC / x3p


<> Code Issues 0 Pull requests 1 Wiki Pulse Graphs

The OpenFMC repository for C/C++ and other code for reading and writing X3P files.

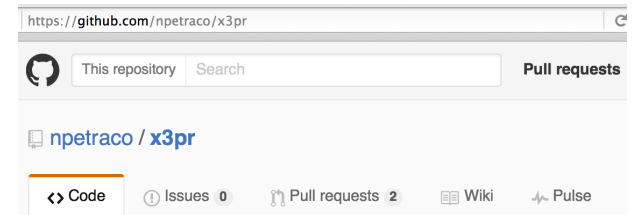


21 commits 1 branch 0

Branch: master New pull request New file Upload files Find file HTTPS

 mbrubake Update readme.

Licence	Remove some vestigial directories.
doc	Remove some vestigial directories.
include/opengps	Remove some vestigial directories.
src	Ryan's changes to the toolbox readme.
README	Update readme.

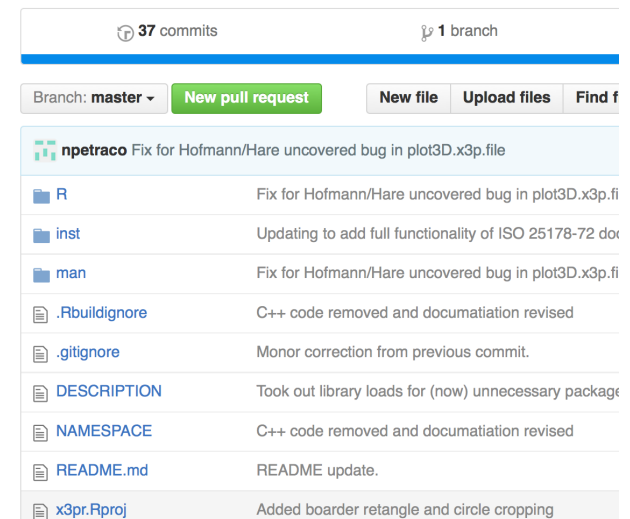


<https://github.com/npetraco/x3pr> Search Pull requests

npetraco / x3pr


<> Code Issues 0 Pull requests 2 Wiki Pulse

Basic read/write capability for the x3p surface metrology format in R —





37 commits 1 branch

Branch: master New pull request New file Upload files Find file

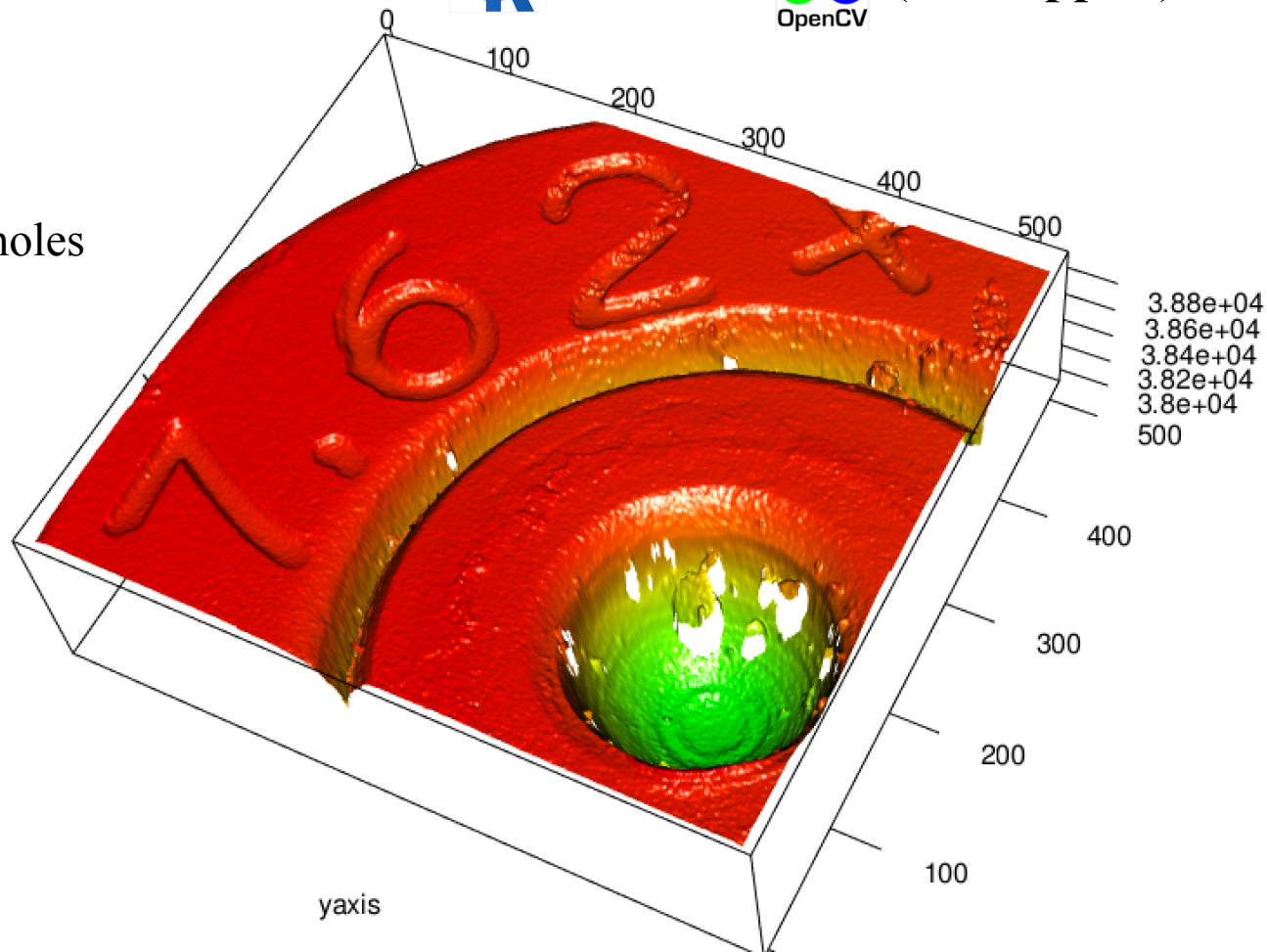
 npetraco Fix for Hofmann/Hare uncovered bug in plot3D.x3p.file

R	Fix for Hofmann/Hare uncovered bug in plot3D.x3p.fi
inst	Updating to add full functionality of ISO 25178-72 do
man	Fix for Hofmann/Hare uncovered bug in plot3D.x3p.fi
.Rbuildignore	C++ code removed and documatiation revised
.gitignore	Monor correction from previous commit.
DESCRIPTION	Took out library loads for (now) unnecessary package
NAMESPACE	C++ code removed and documatiation revised
README.md	README update.
x3pr.Rproj	Added boarder retangle and circle cropping

# Pre-processing Surface Data

- 3D tool mark data usually needs (a lot of...) preprocessing
  - We use a combination of  and C++/ (via **Rcpp<sup>Edd</sup>**) = **feature2**<sup>Petraco</sup>

Possibly fill holes



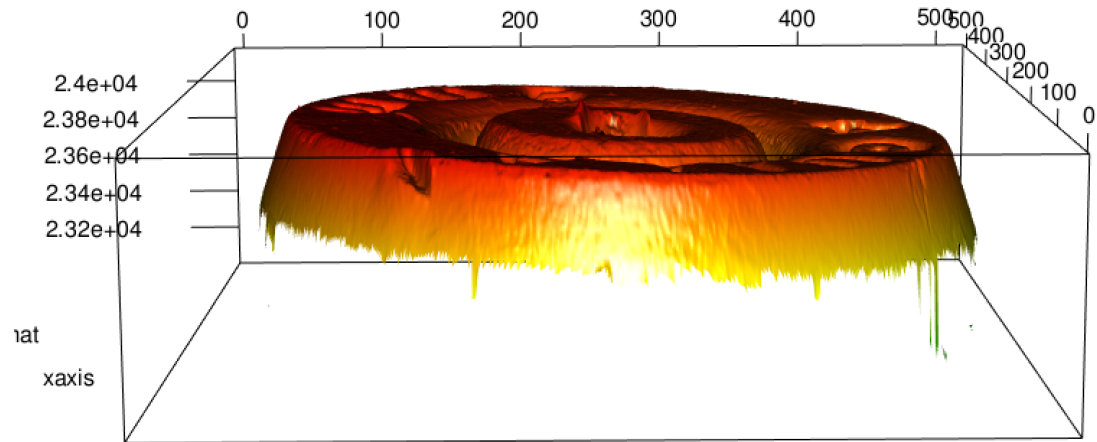


# Preprocessing Surface Data

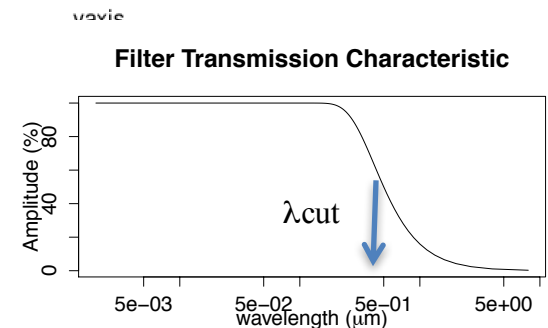
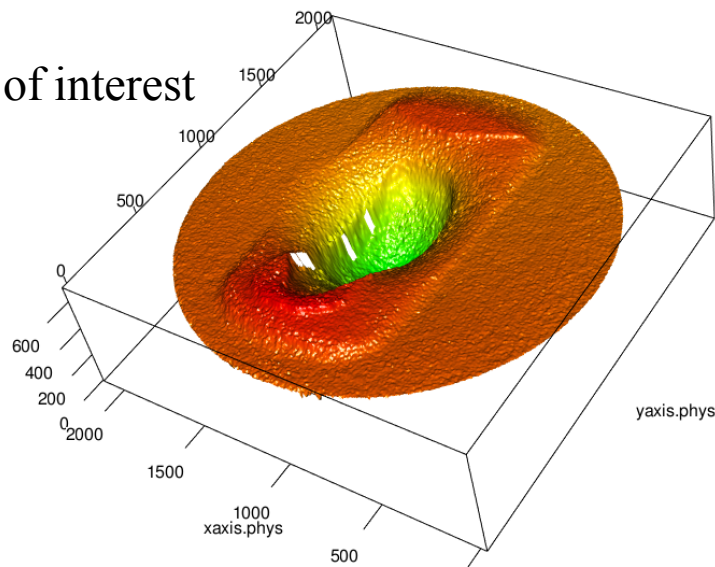
- 3D tool mark data usually needs (a lot of...) preprocessing

- In feature2:

Possibly remove “long range” behavior (leveling, form removal)



Crop out areas of interest



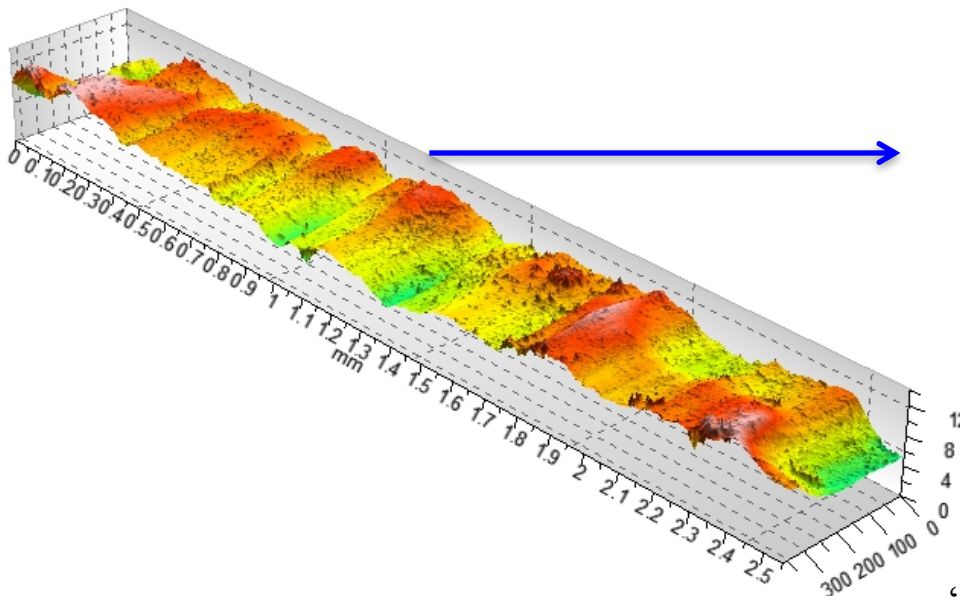
Bandpass filters via:

---

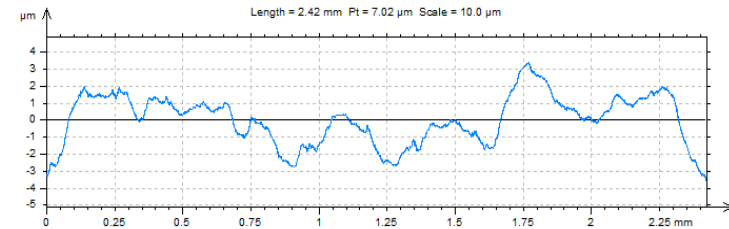
# Good Features are the Key!

- We need a tool mark feature set that is:
  - Large in number
  - (possibly) transnationally invariant
  - (possibly) rotationally invariant
  - Mostly statistically independent
  - **DISCRIMINATORY!**

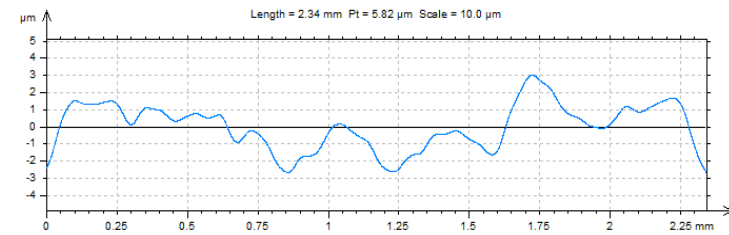
# Toolmark Features



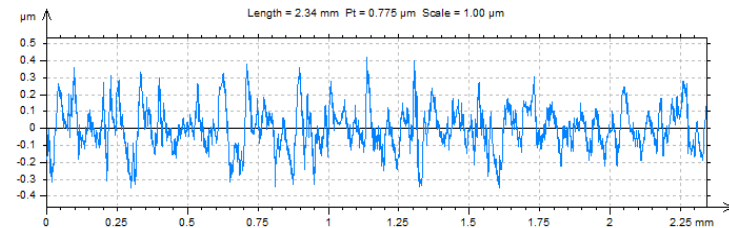
Mean total  
profile:



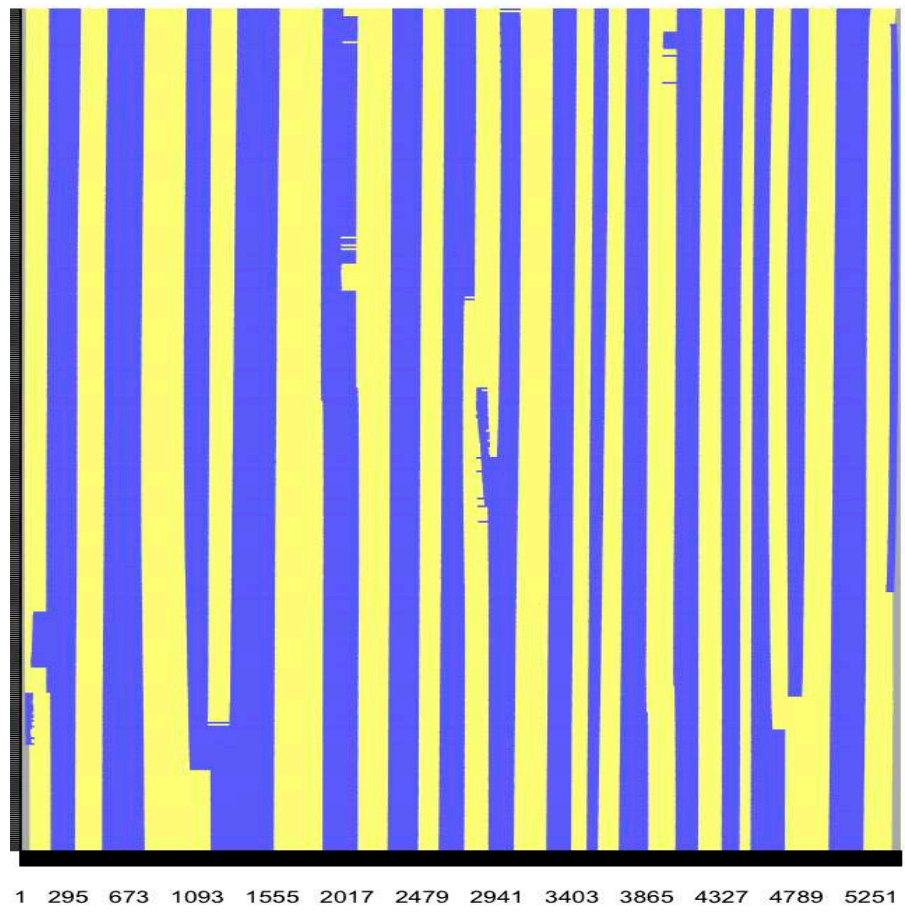
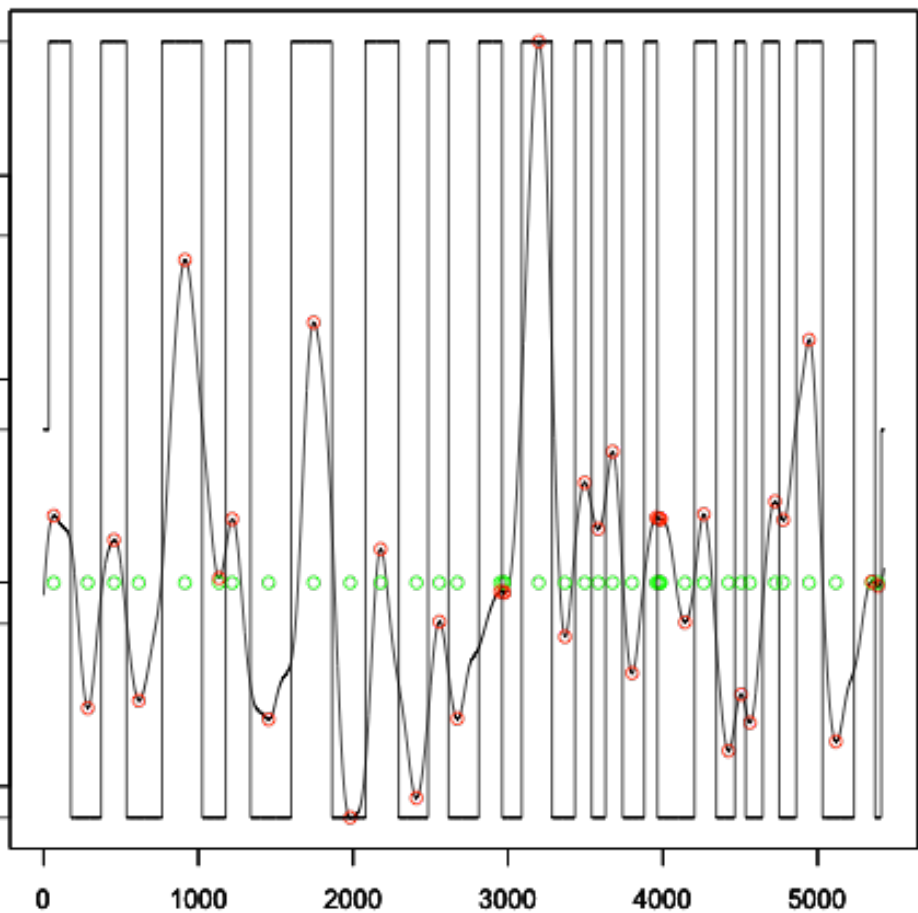
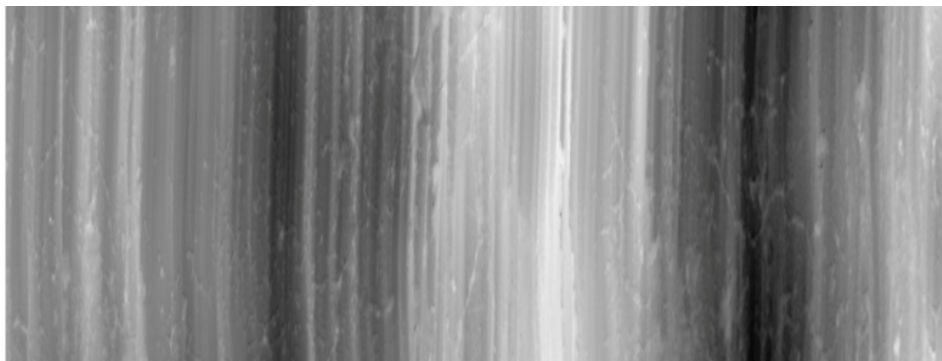
Mean  
“waviness”  
profile:



Mean  
“roughness”  
profile:



Aperture primer shear on a 9mm  
cartridge case fired from the a Glock 19

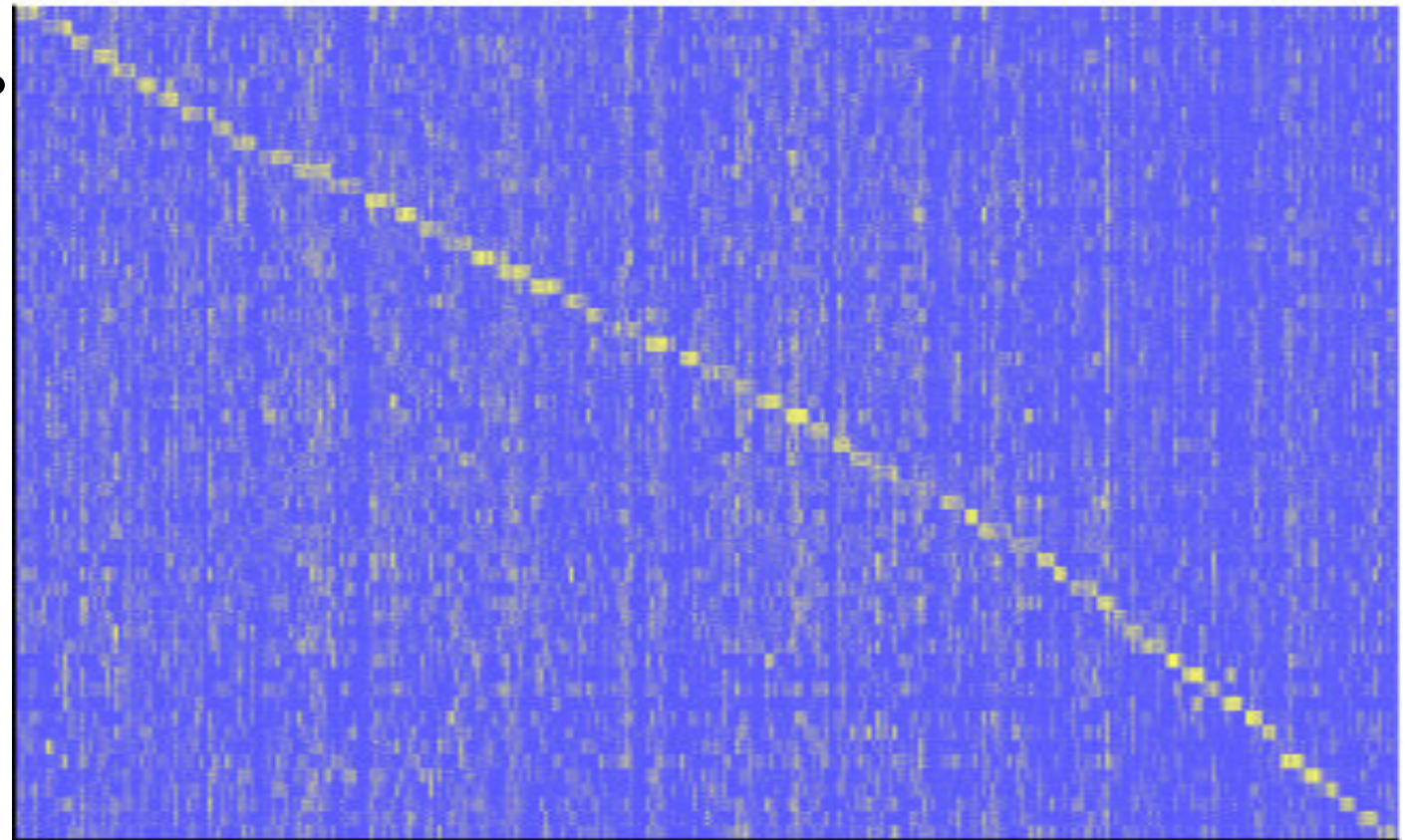
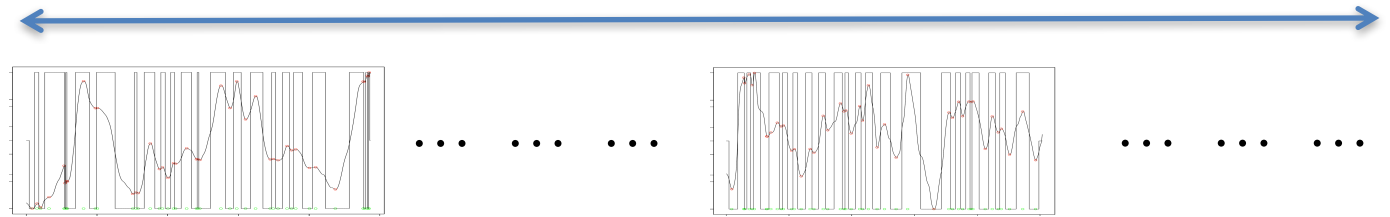
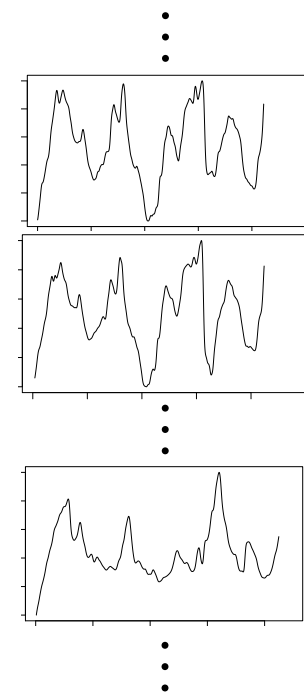


# FAST-Consecutive Matching Striae (CMS)-Space

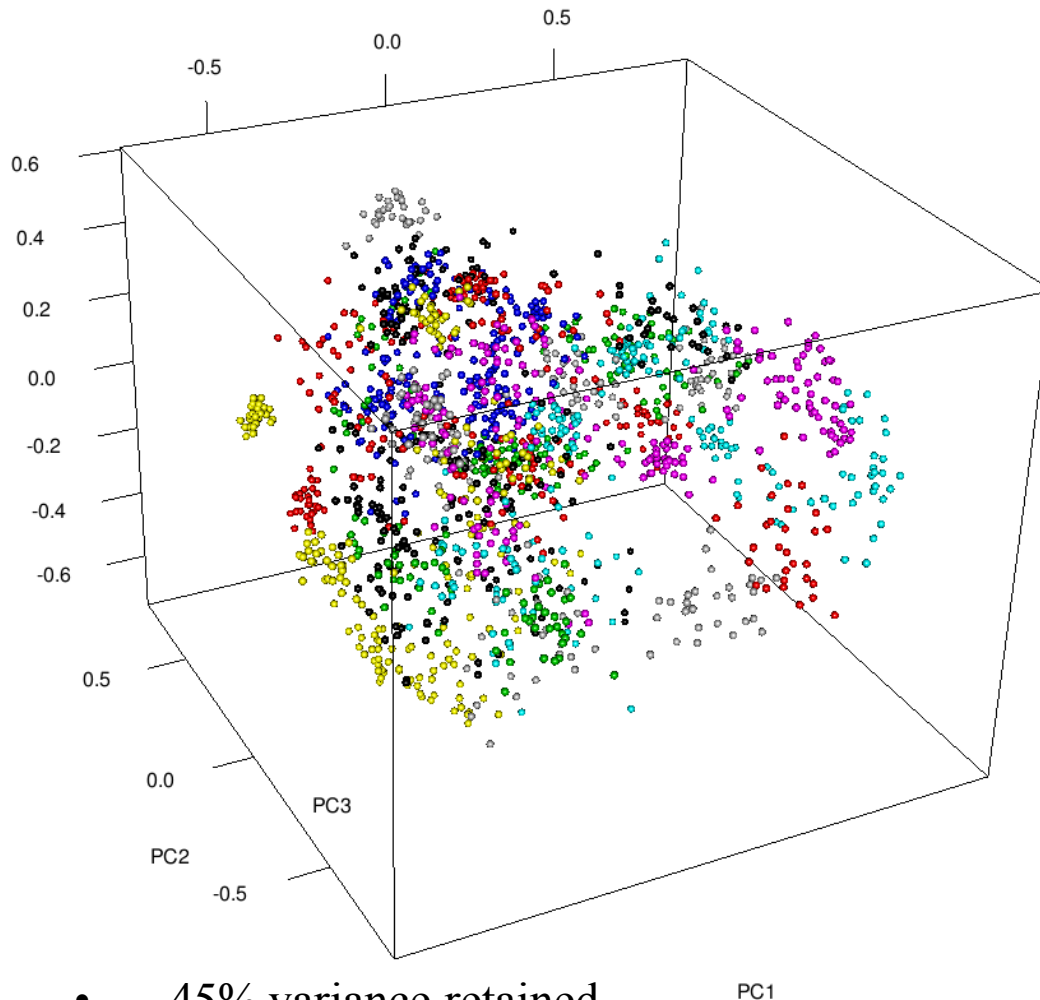
**Biasotti-Murdock dictionary: “Closest Match Ref Set”**

**Rcpp** and **parallel<sup>R-core</sup>**  
packages are great for  
quick and easy speedups

Database/queries



- 3D PCA of 1740 real and simulated mean profiles of striation patterns from 58 screwdrivers:



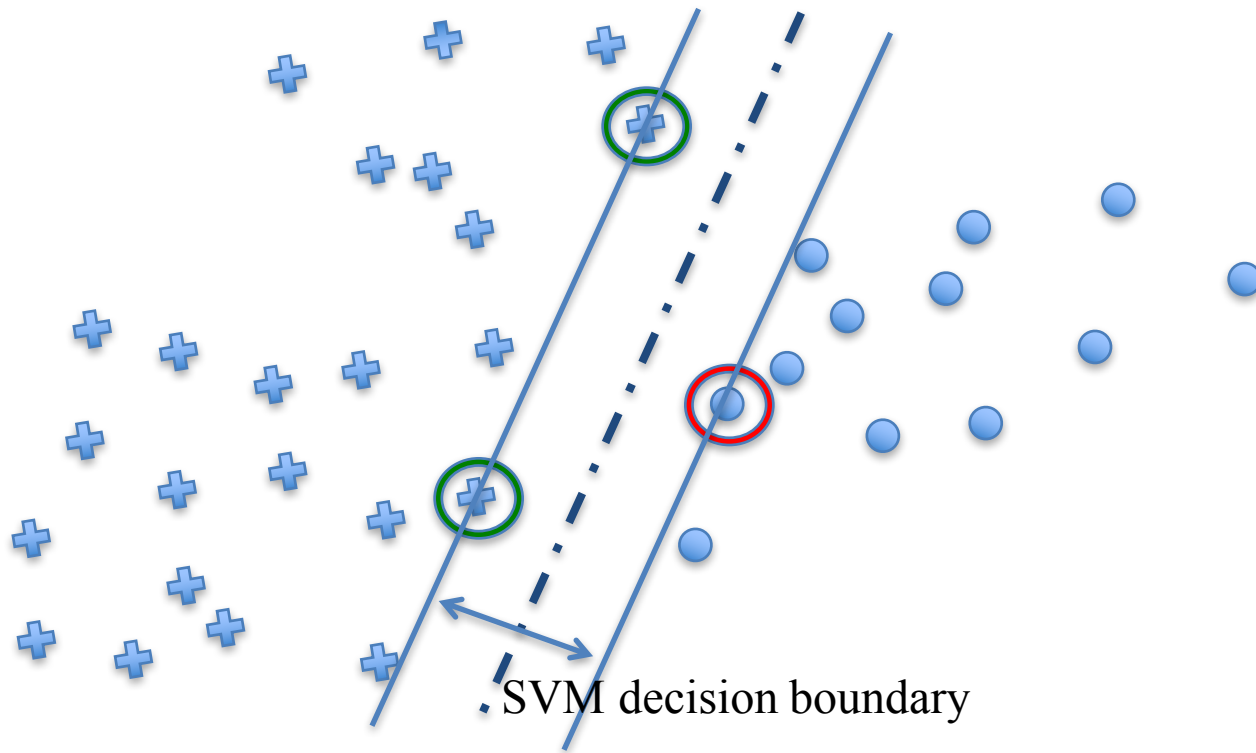
- How many PCs should we use to represent the data??
  - No unique answer
- **FIRST** we *need an algorithm to I.D. a toolmark* to a tool

- ~45% variance retained

PC1

# Support Vector Machines

- Support Vector Machines (SVM) determine efficient association rules
  - *In the absence of specific knowledge of probability densities*



---

# Error Rate Estimation: Machine Learning

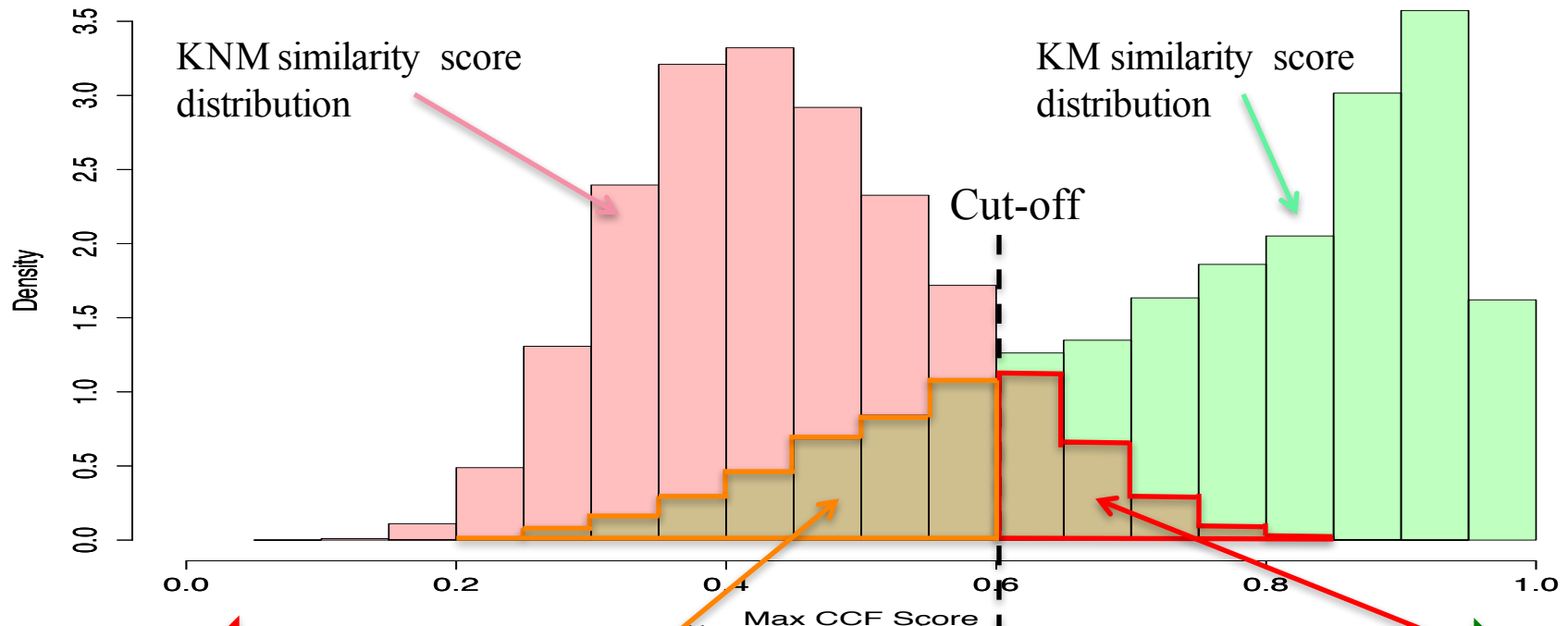
- **Cross-Validation:** hold-out chunks of data set for testing
  - Known since 1940s
  - Most common: **Hold-one-out**
- **Bootstrap:** Randomly selection of observed data (with replacement)
  - Known since the 1970s
  - Can yield *confidence intervals around error rate estimate*
- **The Best:** Small training set, BIG test set



# Error Rate Estimation: Pair-Wise Comparisons

- **Univariate** approaches compute estimates of similarity score distributions for **Known Matches (KM)** and **Known Non-Matches (KNM)**

Max CCF Similarity Score Distributions



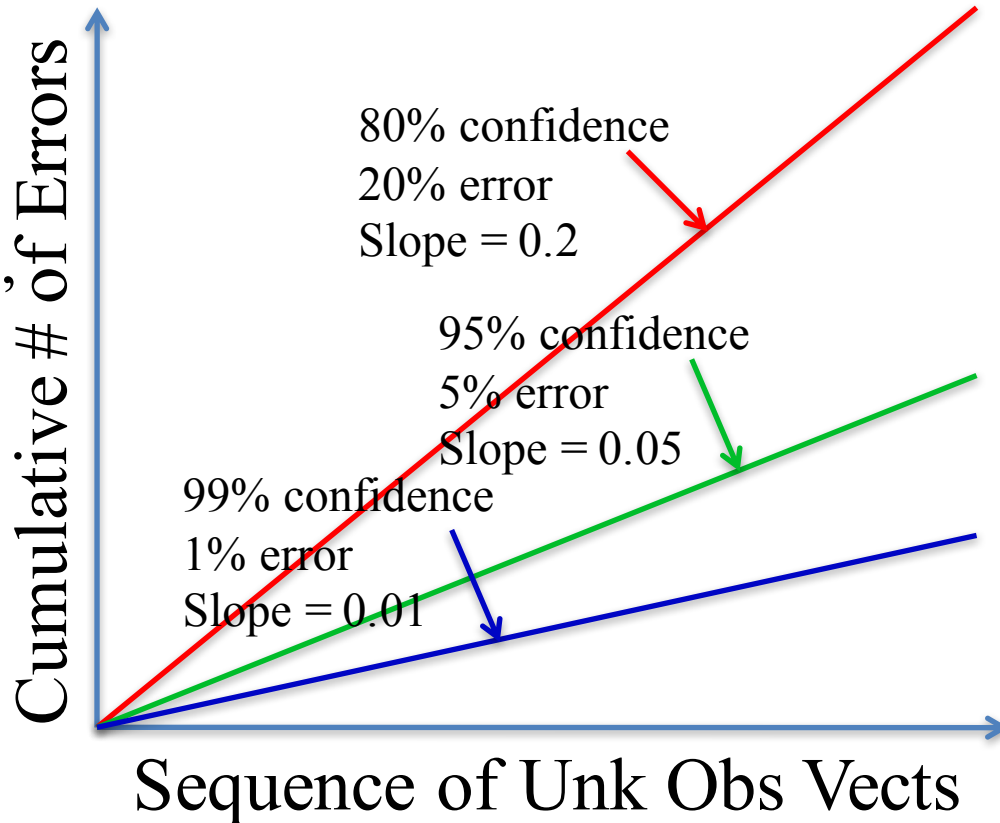
$$\frac{\# \text{False Non-matches}}{\# \text{KM-Comparisons}} = \widehat{\text{FNMR}} \quad \frac{\# \text{False Matches}}{\# \text{KNM-Comparisons}} = \widehat{\text{FMR}}$$

$$\widehat{\text{Error Rate}} = (\# \text{False Non-matches} + \# \text{False Matches}) / \# \text{Comparisons}$$

# How good of a “match” is it?

## Conformal Prediction<sup>Vovk</sup>

- Can give a judge or jury an easy to understand measure of reliability of classification result
  - *Confidence* on a scale of 0%-100%
  - *Testable claim*: Long run I.D. error-rate should be the chosen significance level
- This is an orthodox “frequentist” approach
  - Roots in Algorithmic Information Theory
- Data should be IID but that’s it



# How Conformal Prediction works for us

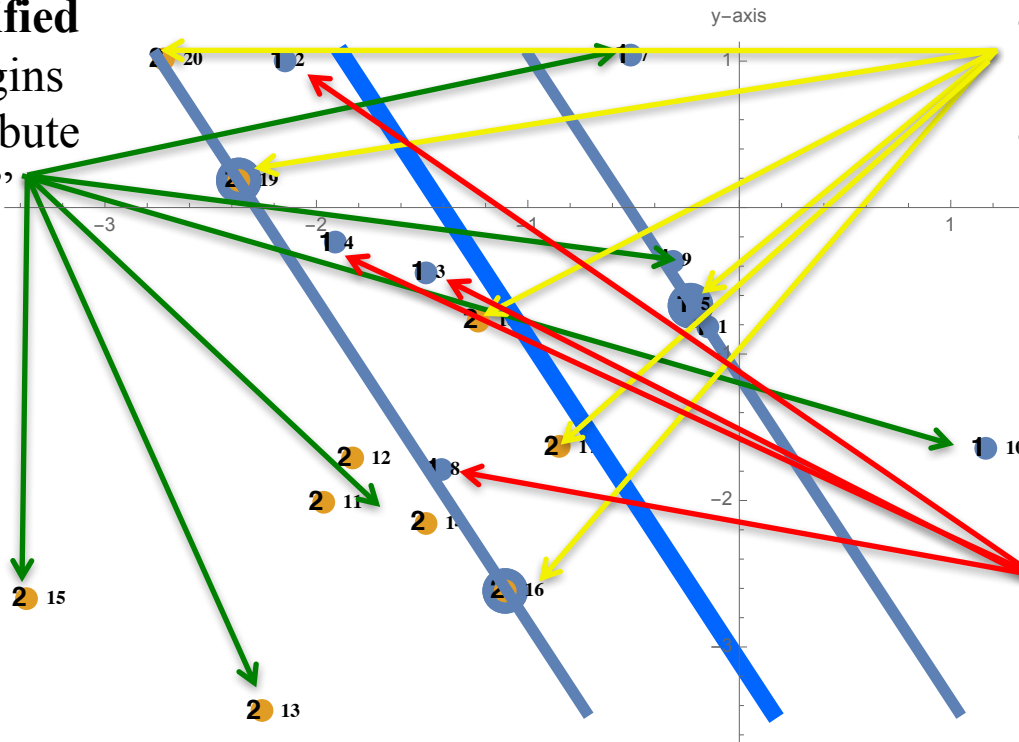
- Given a “bag” of obs with known identities and one obs of unknown identity  $V_{ovk}$ 
  - Estimate how “wrong” labelings are for each observation with a **non-conformity** score (“wrong-iness”)

- For us, one-vs-one SVMs: 
$$t_i = \frac{1}{k-1} \sum_{j=1}^{k(k-1)/2} \lambda_{i,j}$$

$\lambda = 0$

- Correctly classified** and behind margins
- Shouldn't contribute to “wrong-iness”

Intuition:



$0 < \lambda < C$

- Correctly classified but **SVs or marginal**
- Should contribute something to “wrong-iness”


$\lambda = C$

- Wrong**
- Should contribute most “wrong-iness”

# How Conformal Prediction works for us

- Given a “bag” of obs with known identities and one obs of unknown identity<sup>Vovk</sup>
  - Looking at the “wrong-iness” for all the known observations in the bag:
    - Ask: Does labeling- $i$  for the unknown have an unusual amount of “wrong-iness”??:

Given “wrong-iness” for labeling- $i$  of unknown, number of obs with at least as much “wrongi-ness”


$$p_{\text{possible-ID}_i} = \frac{\#\{j \in \{1, 2, \dots, n\} : t_j^{\text{possible-ID}_i} \geq t_{\text{test-pattern}}^{\text{possible-ID}_i}\}}{n} \quad i \in \{1, 2, \dots, k \text{ I.D.s}\}$$

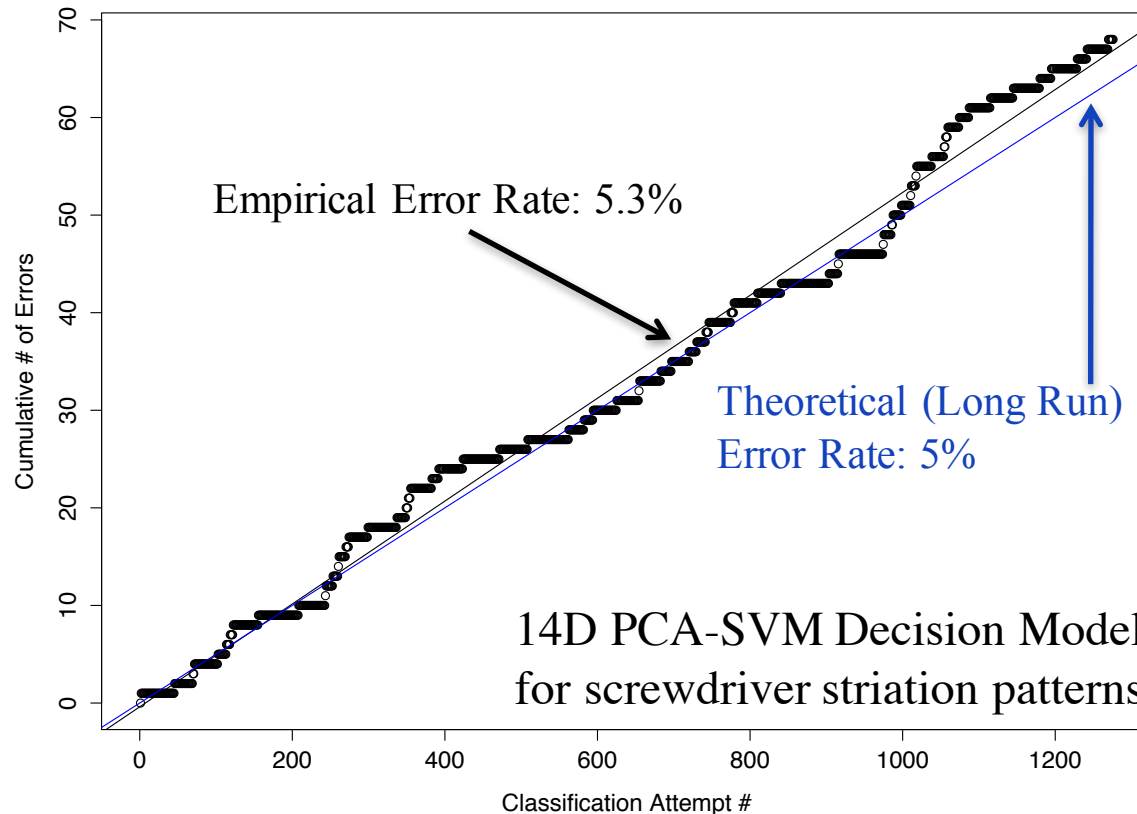
- If not:
  - $p_{\text{possible-ID}_i} \geq$  chosen level of significance  $\alpha$
  - Put  $\text{ID}_i$  in the  $(1 - \alpha) * 100\%$  confidence interval:  $\Gamma^{1-\alpha}$

$$\text{ID}_i \in \Gamma^{1-\alpha} \quad \text{if } p_{\text{ID}_i} \geq \alpha$$

# Conformal Prediction

- For 95%-CPT (PCA-SVM) confidence intervals will not contain the correct I.D. 5% of the time in the long run
  - Straight-forward validation/explanation picture for court

95% CPT Cumulative Errors: On-line Mode



cptID<sup>Petraco</sup> for   
Coming soon...

---

# How good of a “match” is it?

## Efron Empirical Bayes

- An I.D. is output for each questioned tool mark
  - This is a computer “match”
- What’s the **probability the tool is truly the source of the tool mark?**
- Similar problem in genomics for detecting disease from microarray data
  - They use data **and** Bayes’ theorem to get an estimate

# Empirical Bayes

- From Bayes' Theorem we can get<sup>Efron</sup>:

Estimated probability of not a true  
“match” given the algorithms'  
output z-score associated with its  
“match”

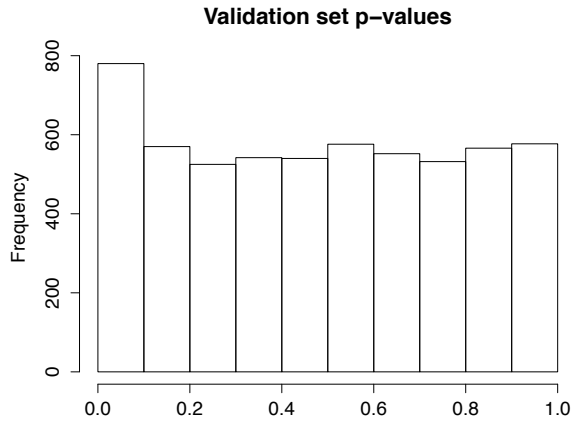
$$\longrightarrow \hat{\Pr}(S^- | z) = \frac{\hat{p}(z | S^-)}{\hat{f}(z)} \hat{\Pr}(S^-)$$

Names: **Posterior error probability (PEP)**<sup>Kall</sup>  
**Local false discovery rate (lfdr)**<sup>Efron</sup>

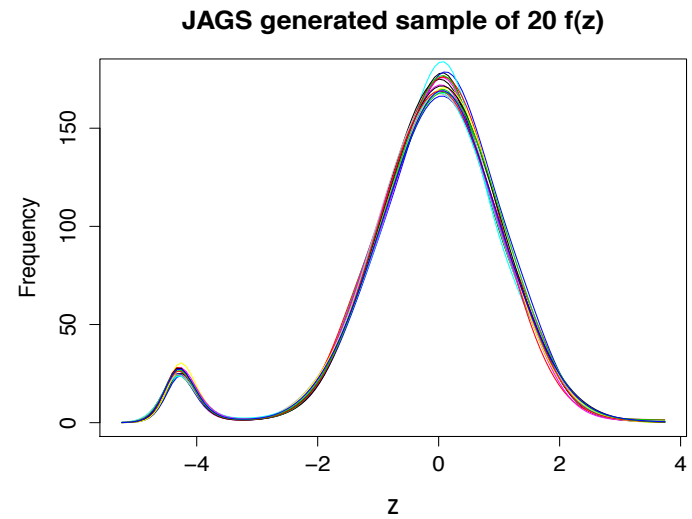
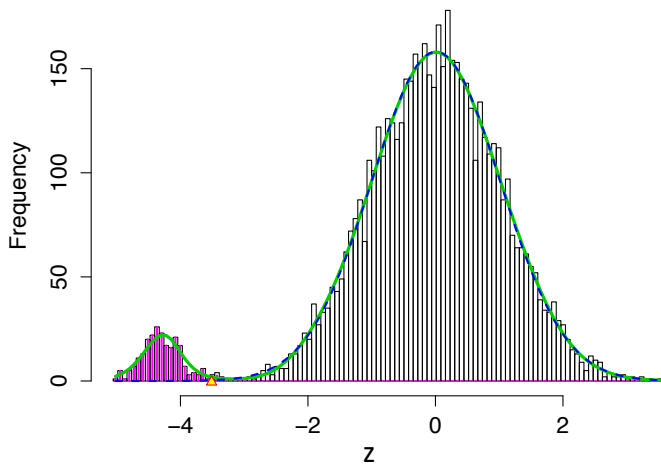
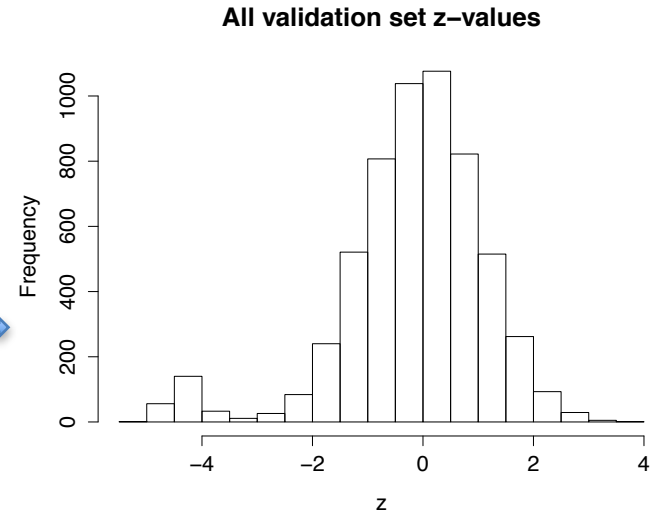
- Suggested interpretation for casework:

$1 - \hat{\Pr}(S^- | z)$  = Estimated “believability” that the specific tool  
produced the tool mark

# Fit local-fdr models



$$\Phi^{-1}(p\text{-values})$$



Use `locfdrlocfdr`

Fit classic Poisson regression for  $f(z)$

Use modified `locfdr`/`JAGS`<sup>JAGS,Plummer</sup> or `Stan`<sup>Stan</sup>

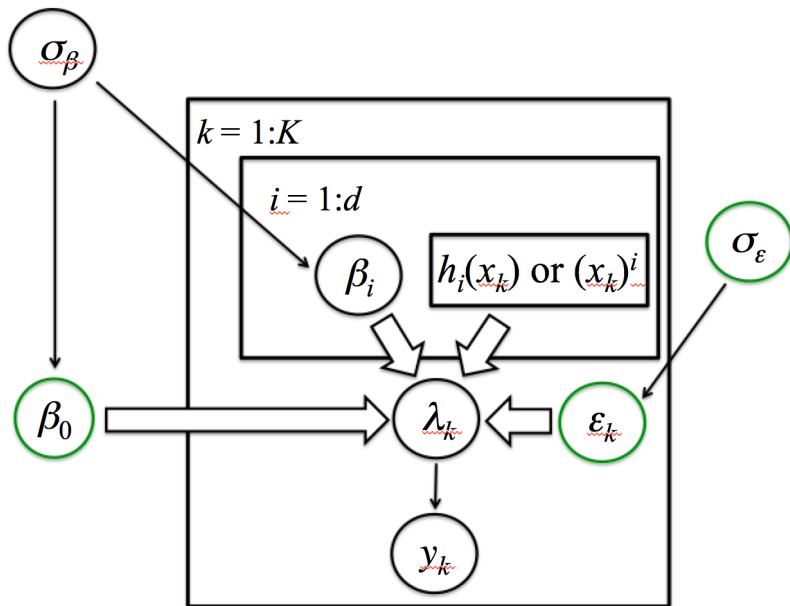
Fit Bayesian hierarchical Poisson regressions



# Bayesian Hierarchical Poisson Regression Details

- To run the Bayesian Estimation we use **JAGS**<sup>Plummer</sup> or **Stan**<sup>Gelman</sup>:

## DAG for the Poisson Regression

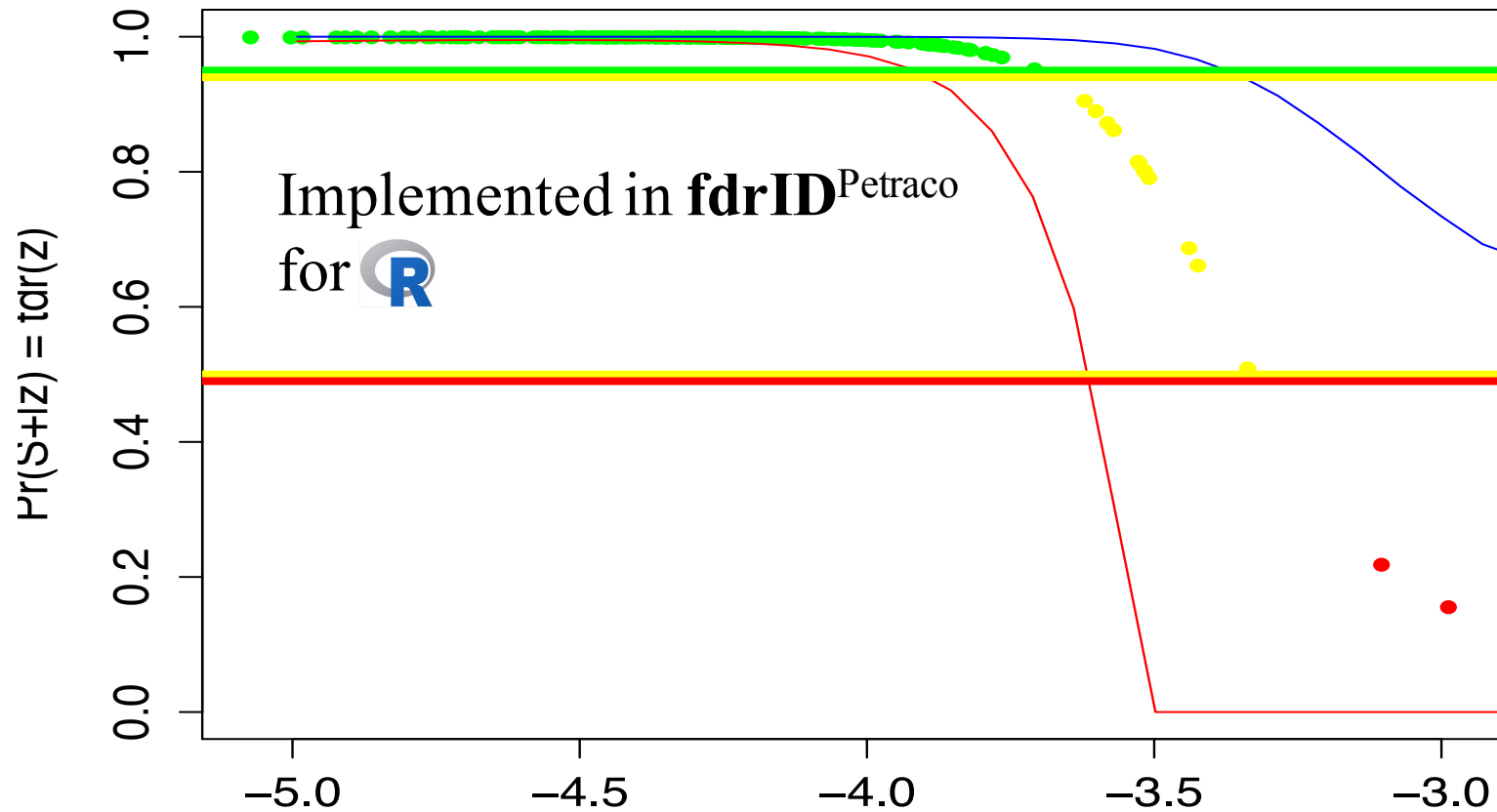


$\sigma_\beta \sim \text{Uniform}(0, 100)$   
 $\sigma_\epsilon \sim \text{Uniform}(0, 100)$   
 $\beta_0 \sim \text{Normal}(0, \sigma_\beta)$   
 $\epsilon_i \sim \text{Normal}(0, \sigma_\epsilon)$   
 $\beta_j \sim \text{Normal}(0, \sigma_\beta)$

Suggested by Gelman

# A Bayesian Hierarchical Model: Believability Curve

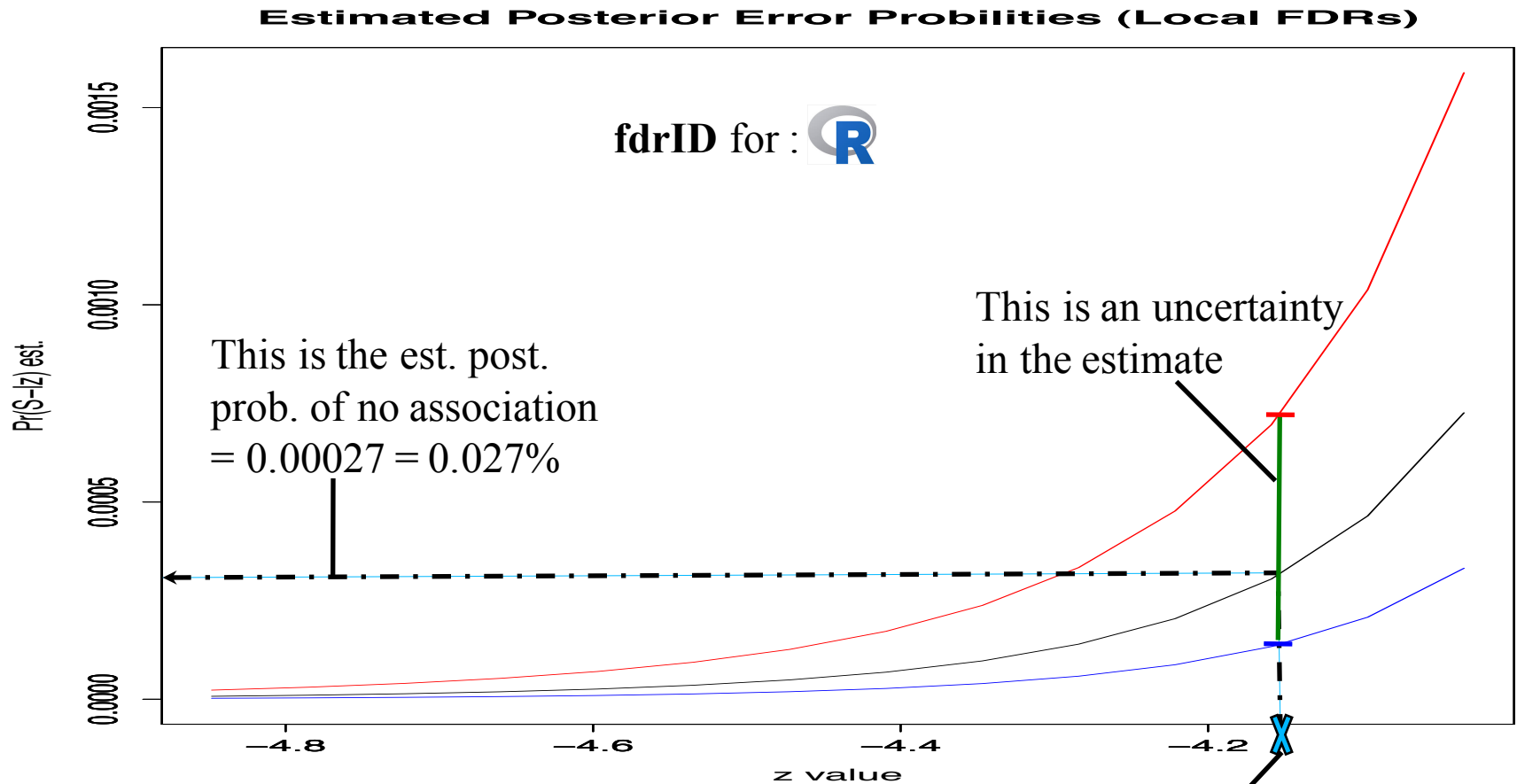
## Posterior Association Probability (Believability...)



JAGS MCMC Bayesian over-dispersed Poisson with intercept, on test set

# Empirical Bayes'

- Model's use with crime scene "unknowns":



Computer outputs "match" for:

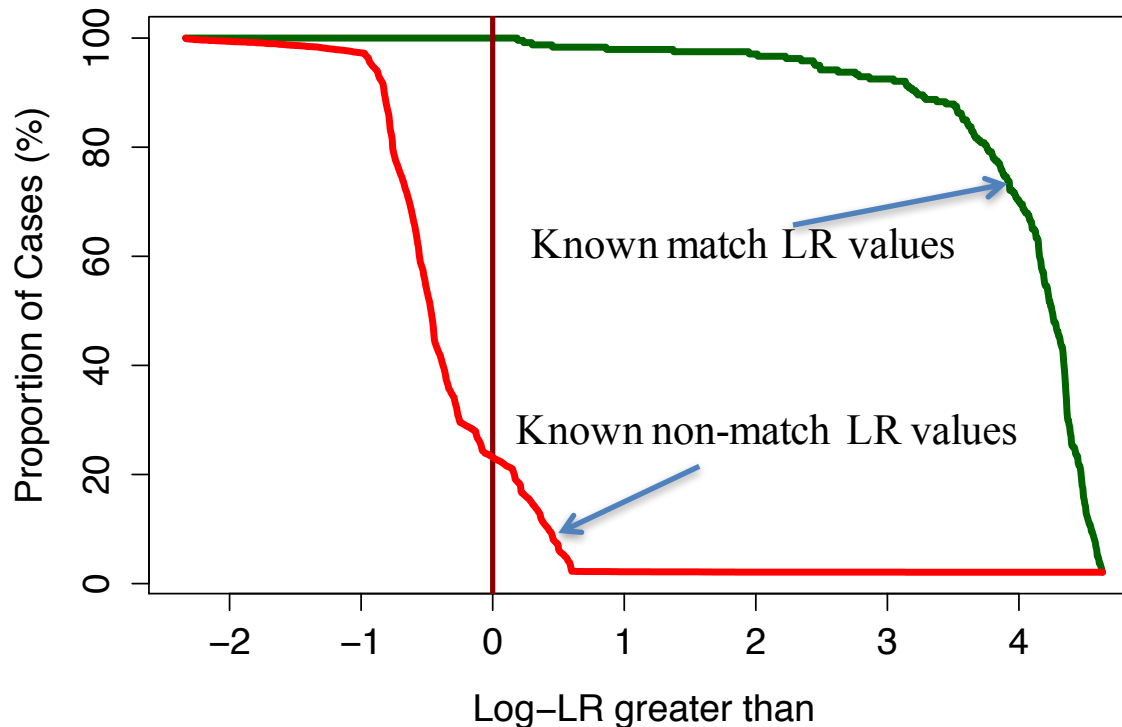
unknown crime scene toolmarks-with knowns from "Bob the burglar" tools

# Likelihood Ratios from Empirical Bayes

- Using the fit posteriors and priors we can obtain the likelihood ratios

$$\widehat{\text{LR}}(z) = \frac{\widehat{\text{Pr}}(H_p|E)}{\widehat{\text{Pr}}(H_d|E)} \bigg/ \frac{\widehat{\text{Pr}}(H_p)}{\widehat{\text{Pr}}(H_d)} = \frac{\widehat{\text{tdr}}(z) \hat{\pi}_0}{\widehat{\text{fdr}}(z) (1 - \hat{\pi}_0)}$$

**Tippett Plot**



# Bayesian Match Probabilities from CMS

- 2007 Neel and Wells study<sup>Neel, Wevers, Buckleton</sup>:
  - Count the number of each type of CMS run for KM and KNM comparisons
    - A CMS type is its run length:
      - 4X means 4 matching adjacent lines in a comparison of two striation patterns

914 KM comparisons

1411 KNM comparisons

Number observed	CMS run lengths:				Number observed	CMS run lengths:			
	2X	3X	4X	...		2X	3X	4X	...
0	508	612	694	...	0	771	1239	1357	...
1	186	172	135	...	1	298	124	47	...
2	109	59	43	...	2	143	35	4	...
3	39	29	19	...	3	84	10	2	...
4	21	15	16	...	4	46	2	1	...
5	10	9	2	...	5	21	1	0	...
6	4	9	1	...	6	13	0	0	...
7	10	6	3	...	7	14	0	0	...
8	14	2	0	...	8	6	0	0	...
>8	13	1	1	...	>8	15	0	0	...

Model each column of counts as arising from a multinomial distribution with Dirichlet prior

# Bayesian Match Probabilities from CMS

- Updated CMS run length probabilities:

KM comparisons

Number observed	CMS run lengths:			
	2X	3X	4X	...
0	0.550	0.663	0.752	...
1	0.202	0.187	0.147	...
2	0.119	0.065	0.047	...
3	0.043	0.032	0.022	...
4	0.024	0.018	0.019	...
5	0.012	0.011	0.003	...
6	0.005	0.011	0.002	...
7	0.012	0.008	0.004	...
8	0.016	0.003	0.001	...
>8	0.015	0.002	0.002	...

KNM comparisons

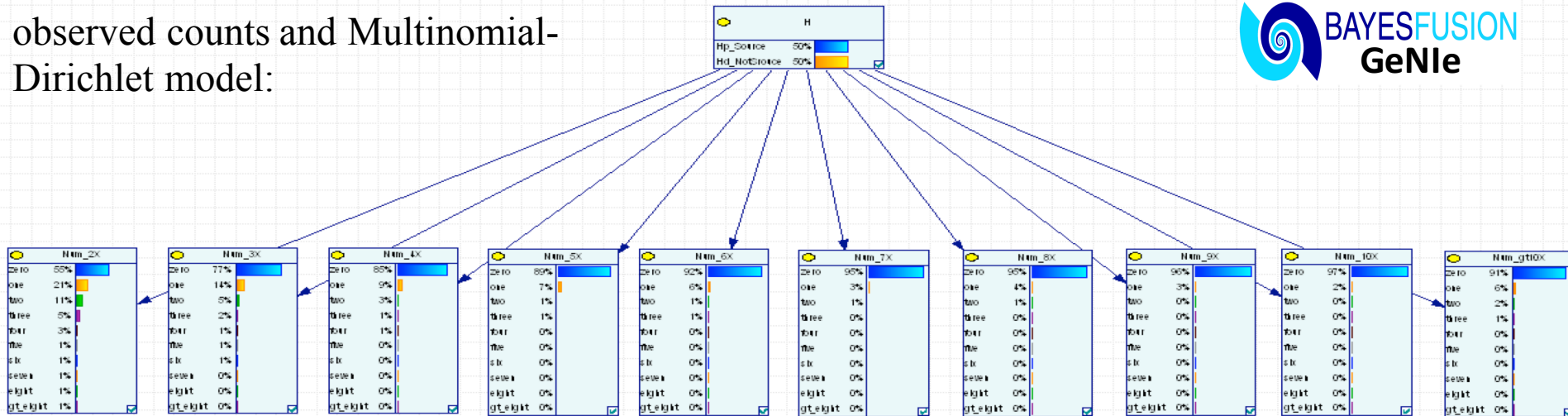
Number observed	CMS run lengths:			
	2X	3X	4X	...
0	0.5440	0.8726	0.9556	...
1	0.2099	0.0880	0.0338	...
2	0.1010	0.0254	0.0035	...
3	0.0598	0.0078	0.0021	...
4	0.0332	0.0021	0.0014	...
5	0.0155	0.0014	0.0007	...
6	0.0099	0.0007	0.0007	...
7	0.0105	0.0007	0.0007	...
8	0.0049	0.0006	0.0007	...
>8	0.0113	0.0007	0.0007	...

- So what can we use these for??
  - Lot's of stuff, but we put them into a **Bayesian network**:
    - BN model for Match/Non-match probabilities given observed numbers of CMS runs

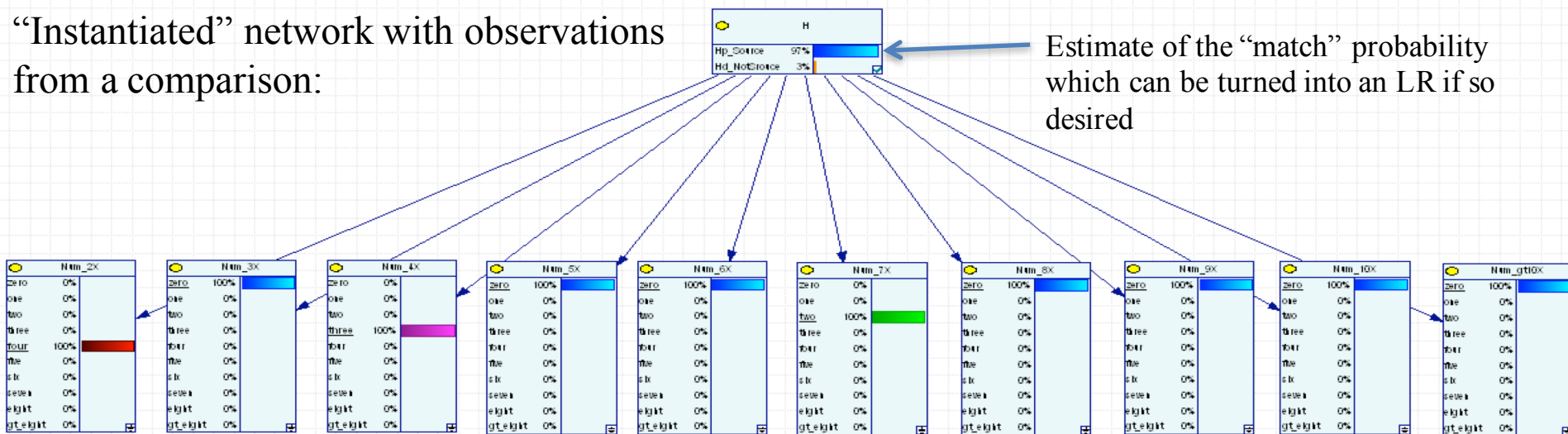
# Bayesian Networks



“Prior” network based on Neel and Wells  
observed counts and Multinomial-Dirichlet model:



“Instantiated” network with observations  
from a comparison:



---

# Future Directions

- **Clean up:** cptID, feature2, fdrID
- **GUI modules** for common toolmark comparison tasks/calculations using 3D microscope data
- **2D features** for toolmark impressions
- **Parallel/GPU/FPGA** implementation of computationally intensive routines e.g. ALMA Correlator for astronomy data
  - Especially for retrieving “relevant pop/best match” reference sets
- **Uncertainty for Bayesian Networks**
  - Models, parameters...



---

# References

**Zheng:** <http://www.nist.gov/forensics/ballisticsdb/>

**Lillien:**

- <http://www.openfmc.org/>
- <http://www.cadreforensics.com/>

**Brubaker:** <https://github.com/OpenFMC/x3p>

**Petraco:**

- <https://github.com/npetraco/x3pr>
- <https://github.com/npetraco/feature2>
- <https://github.com/npetraco/cptID>
- <https://github.com/npetraco/fdrID>

**Edd:**

- <https://cran.r-project.org/web/packages/Rcpp/index.html>
- <http://dirk.eddelbuettel.com/code/rcpp.html>

**OpenCV:** <http://opencv.org/>

**Whitcher:** <https://cran.r-project.org/web/packages/waveslim/index.html>

**R-Core:** <https://www.r-project.org/>

**Vovk:** <http://www.alrw.net/>

**Efron:**

- Efron, B. “Large-Scale Inference: Empirical Bayes Methods for Estimation, Testing, and Prediction”, Cambridge, 2013.

---

# References

**locfdr:** <https://cran.r-project.org/web/packages/locfdr/index.html>

**JAGS:**

- <http://mcmc-jags.sourceforge.net/>
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